SLAS152D - DECEMBER 1997 - REVISED APRIL 2004

- 12-Bit Voltage Output DAC
- Programmable Settling Time vs Power Consumption

3  $\mu$ s in Fast Mode 9  $\mu$ s in Slow Mode

- Ultra Low Power Consumption:
   900 μW Typ in Slow Mode at 3 V
   2.1 mW Typ in Fast Mode at 3 V
- Differential Nonlinearity . . . < 0.5 LSB Typ
- Compatible With TMS320 and SPI Serial Ports
- Power-Down Mode (10 nA)
- Buffered High-Impedance Reference Input

#### description

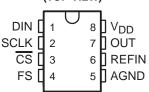
The TLV5616 is a 12-bit voltage output digital-to-analog converter (DAC) with a flexible 4-wire serial interface. The 4-wire serial interface allows glueless interface to TMS320, SPI, QSPI, and Microwire serial ports. The TLV5616 is programmed with a 16-bit serial string containing 4 control and 12 data bits. Developed for a wide range of supply voltages, the TLV5616 can operate from 2.7 V to 5.5 V.

- Voltage Output Range . . . 2 Times the Reference Input Voltage
- Monotonic Over Temperature
- Available in MSOP Package

#### applications

- Digital Servo Control Loops
- Digital Offset and Gain Adjustment
- Industrial Process Control
- Machine and Motion Control Devices
- Mass Storage Devices

#### D, DGK, OR P PACKAGE (TOP VIEW)



The resistor string output voltage is buffered by a x2 gain rail-to-rail output buffer. The buffer features a Class AB output stage to improve stability and reduce settling time. The settling time of the DAC is programmable to allow the designer to optimize speed versus power dissipation. The settling time is chosen by the control bits within the 16-bit serial input string. A high-impedance buffer is integrated on the REFIN terminal to reduce the need for a low source impedance drive to the terminal.

Implemented with a CMOS process, the TLV5616 is designed for single supply operation from 2.7 V to 5.5 V. The device is available in an 8-terminal SOIC package. The TLV5616C is characterized for operation from  $0^{\circ}$ C to  $70^{\circ}$ C. The TLV5616I is characterized for operation from  $-40^{\circ}$ C to  $85^{\circ}$ C.

#### AVAILABLE OPTIONS

		PACKAGE	
TA	SMALL OUTLINE† (D)	MSOP (DGK)	PLASTIC DIP (P)
0°C to 70°C	TLV5616CD	TLV5616CDGK	TLV5616CP
-40°C to 85°C	TLV5616ID	TLV5616IDGK	TLV5616IP

† Available in tape and reel as the TLV5616CDR and the TLV5616IDR

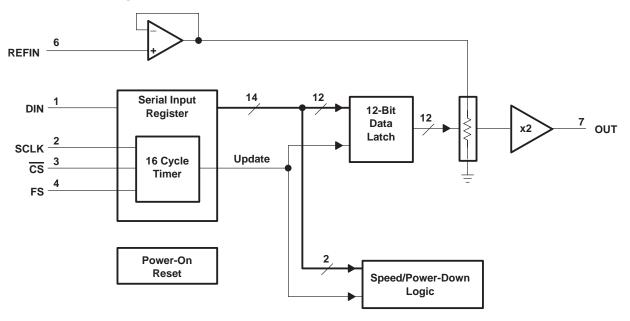


Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.



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## functional block diagram



## **Terminal Functions**

TERMI	TERMINAL		
NAME	NO.	1/0	DESCRIPTION
AGND	5		Analog ground
CS	3	- 1	Chip select. Digital input used to enable and disable inputs, active low.
DIN	1	I	Serial digital data input
FS	4	I	Frame sync. Digital input used for 4-wire serial interfaces such as the TMS320 DSP interface.
OUT	7	0	DAC analog output
REFIN	6	Ι	Reference analog input voltage
SCLK	2	Ī	Serial digital clock input
$V_{DD}$	8		Positive power supply



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# absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage (V <sub>DD</sub> to AGND)	
Reference input voltage range	
Digital input voltage range	
Operating free-air temperature range, T <sub>A</sub> : TLV5616C	
TLV5616I	40°C to 85°C
Storage temperature range, T <sub>Stq</sub>	65°C to 150°C
Lead temperature 1.6 mm (1/16 inch) from case for 10 seconds	260°C

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

#### recommended operating conditions

		MII	I NOM	MAX	UNIT
Cupply voltage V	V <sub>DD</sub> = 5 V	4.:	5 5	5.5	V
Supply voltage, VDD	V <sub>DD</sub> = 3 V	2.	7 3	3.3	V
High lovel digital input valtage V	DV <sub>DD</sub> = 2.7 V		2		V
	DV <sub>DD</sub> = 5.5 V	2.	ļ		V
Low lovel digital input valtage. Viv	DV <sub>DD</sub> = 2.7 V			0.6	V
Low-level digital input voltage, VIL	DV <sub>DD</sub> = 5.5 V	4.5 5 5.5  2.7 3 3.3  V  2 V  2.4 V  V  2.4 V  O.6 V  See Note 1) AGND 2.048 VDD-1.5 V  ace Note 1) AGND 1.024 VDD-1.5 V  2 10 k  100 p  20 M  0 70 °	V		
Reference voltage, V <sub>ref</sub> to REFIN terminal	V <sub>DD</sub> = 5 V (see Note 1)	AGNI	2.048	V <sub>DD</sub> -1.5	V
Reference voltage, V <sub>ref</sub> to REFIN terminal	V <sub>DD</sub> = 3 V (see Note 1)	AGNI	1.024	V <sub>DD</sub> -1.5	V
Load resistance, R <sub>L</sub>			2 10		kΩ
Supply voltage, VDD  VDD = 3 V  VDD = 2.7 V  DVDD = 5.5 V  Low-level digital input voltage, VIL  Reference voltage, Vref to REFIN terminal Reference voltage, Vref to REFIN terminal VDD = 5 V (see Note 1)  AG  Reference voltage, Vref to REFIN terminal VDD = 3 V (see Note 1)  AG  Load resistance, RL  Load capacitance, CL  Clock frequency, fCLK  TLV5616C			100	pF	
Clock frequency, fCLK				20	MHz
On creating free cir temperature T.	TLV5616C		)	70	°C
Operating free-air temperature, 14	TLV5616I	-4	)	85	°C

NOTE 1: Due to the x2 output buffer, a reference input voltage ≥ V<sub>DD/2</sub> causes clipping of the transfer function.

# electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

#### power supply

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT		
			$V_{DD} = 5 \text{ V, VREF} = 2.048 \text{ V,}$ No load,	Fast		0.9	1.35	mA
	Power supply current		All inputs = AGND or V <sub>DD</sub> , DAC latch = 0x800	Slow		0.4	0.6	mA
<sup>I</sup> DD	rower supply current	$V_{DD} = 3 \text{ V}, \text{ VREF} = 1.024 \text{ V}$ No load,	Fast		0.7	1.1	mA	
		All inputs = AGND or V <sub>DD</sub> , DAC latch = 0x800	Slow		0.3	0.45	mA	
	Power down supply current (see Figure	12)				10		nA
PSRR	Power supply rejection ratio  Zero scale  Full scale		See Note 2		-80		dB	
PSKK			See Note 3		-80		uБ	
	Power on threshold voltage, POR			_	2		V	

NOTES: 2. Power supply rejection ratio at zero scale is measured by varying  $V_{DD}$  and is given by: PSRR = 20 log [(EZS( $V_{DD}$ max) - EZS( $V_{DD}$ min))/ $V_{DD}$ max]

3. Power supply rejection ratio at full scale is measured by varying  $V_{DD}$  and is given by: PSRR = 20 log [(E<sub>G</sub>(V<sub>DD</sub>max) – E<sub>G</sub>(V<sub>DD</sub>min))/V<sub>DD</sub>max]



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## electrical characteristics over recommended operating free-air temperature range (unless otherwise noted) (continued)

#### static DAC specifications $R_L = 10 \text{ k}\Omega$ , $C_L = 100 \text{ pF}$

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
	Resolution			12	12	bits
INL	Integral nonlinearity	See Note 4		± 1.9	±4	LSB
DNL	Differential nonlinearity	See Note 5		± 0.5	± 1	LSB
EZS	Zero-scale error (offset error at zero scale)	See Note 6			±10	mV
	Zero-scale-error temperature coefficient	See Note 7		10		ppm/°C
EG	Gain error	See Note 8			±0.6	% of FS voltage
	Gain-error temperature coefficient	See Note 9		10		ppm/°C

- NOTES: 4. The relative accuracy or integral nonlinearity (INL) sometimes referred to as linearity error, is the maximum deviation of the output from the line between zero and full scale excluding the effects of zero code and full-scale errors. Tested from code 10 to code 4095.
  - 5. The differential nonlinearity (DNL) sometimes referred to as differential error, is the difference between the measured and ideal 1 LSB amplitude change of any two adjacent codes. Monotonic means the output voltage changes in the same direction (or remains constant) as a change in the digital input code. Tested from code 10 to code 4095.
  - 6. Zero-scale error is the deviation from zero voltage output when the digital input code is zero.

  - 7. Zero-scale-error temperature coefficient is given by:  $E_{ZS}$  TC =  $[E_{ZS}$  ( $T_{max}$ )  $E_{ZS}$  ( $T_{min}$ )]/ $V_{ref}$  × 10<sup>6</sup>/( $T_{max}$   $T_{min}$ ). 8. Gain error is the deviation from the ideal output ( $2V_{ref}$  1 LSB) with an output load of 10 k $\Omega$  excluding the effects of the zero-error. 9. Gain temperature coefficient is given by:  $E_{G}$  TC =  $[E_{G}(T_{max}) E_{G}(T_{min})]/V_{ref}$  × 10<sup>6</sup>/( $T_{max}$   $T_{min}$ ).

#### output specifications

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
VO	Voltage output range	$R_L = 10 \text{ k}\Omega$	0		AV <sub>DD</sub> -0.1	V
	Output load regulation accuracy	$R_L = 2 \text{ k}\Omega$ , vs 10 k $\Omega$		0.1	±0.25	% of FS voltage

#### reference input (REF)

	1 \ /						
	PARAMETER	TEST CONDITIONS		MIN	TYP	MAX	UNIT
VI	Input voltage range			0		V <sub>DD</sub> -1.5	V
R <sub>I</sub>	Input resistance				10		$M\Omega$
Cl	Input capacitance				5		рF
	Defense a legal based ability	BEEIN 0.0 V + 4.004 V do	Slow		525		kHz
	Reference input bandwidth	REFIN = $0.2 V_{pp} + 1.024 V dc$	Fast		1.3		MHz
	Reference feed through	REFIN = 1 V <sub>pp</sub> at 1 kHz + 1.024 V dc (see Note 10)			-75		dB

NOTE 10: Reference feedthrough is measured at the DAC output with an input code = 0x000.

#### digital inputs

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
lн	High-level digital input current	$V_I = V_{DD}$			±1	μΑ
IIL	Low-level digital input current	V <sub>I</sub> = 0 V			±1	μΑ
Cl	Input capacitance			3		pF



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# operating characteristics over recommended operating free-air temperature range (unless otherwise noted)

#### analog output dynamic performance

	PARAMETER	TES	ST CONDITIONS		MIN	TYP	MAX	UNIT	
	Output and the Constitution	$R_L = 10 \text{ k}\Omega$ ,	C <sub>L</sub> = 100 pF,	Fast		3	5.5	_	
ts(FS)	Output settling time, full scale	See Note 11		Slow		9	20	μs	
	Output as III as Care as date as da	$R_L = 10 \text{ k}\Omega$ ,	$C_L = 100 pF$ ,	Fast		1		μs	
ts(CC)	Output settling time, code to code	See Note 12		Slow		2		μs	
0.0	Olemante	$R_L = 10 \text{ k}\Omega$ ,	C <sub>L</sub> = 100 pF,	Fast		3.6		\// -	
SR	Slew rate	See Note 13		Slow		0.9		V/µs	
	Glitch energy	Code transition	from 0x7FF to 0x80	0		10		nV-s	
S/N	Signal to noise					74		dB	
S/(N+D)	Signal to noise + distortion	fs = 400 KSPS fout = 1.1 kHz,				66		dB	
THD	Total harmonic distortion	$R_L = 10 \text{ k}\Omega$ , $C_L = BW = 20 \text{ kHz}$	$C_L = 100 pF$ ,			-68		dB	
	Spurious free dynamic range	]				70		dB	

- NOTES: 11. Settling time is the time for the output signal to remain within ±0.5 LSB of the final measured value for a digital input code change of 0x080 to 0x3FF or 0x3FF to 0x080. Not tested, ensured by design.
  - 12. Settling time is the time for the output signal to remain within  $\pm$  0.5 LSB of the final measured value for a digital input code change of one count. Code change from 0x1FF to 0x200. Not tested, ensured by design.
  - 13. Slew rate determines the time it takes for a change of the DAC output from 10% to 90% full-scale voltage.

#### digital input timing requirements

		MIN	NOM	MAX	UNIT
tsu(CS-FS)	Setup time, CS low before FS↓	10			ns
tsu(FS-CK)	Setup time, FS low before first negative SCLK edge	8			ns
tsu(C16-FS)	Setup time, sixteenth negative edge after FS low on which bit D0 is sampled before rising edge of FS	10			ns
tsu(C16-CS)	Setup time, sixteenth positive SCLK edge (first positive after D0 is sampled) before $\overline{CS}$ rising edge. If FS is used instead of the sixteenth positive edge to update the DAC, then the setup time is between the FS rising edge and $\overline{CS}$ rising edge.	10			ns
t <sub>wH</sub>	Pulse duration, SCLK high	25			ns
t <sub>wL</sub>	Pulse duration, SCLK low	25			ns
tsu(D)	Setup time, data ready before SCLK falling edge	8			ns
th(D)	Hold time, data held valid after SCLK falling edge	5			ns
twH(FS)	Pulse duration, FS high	20			ns



## PARAMETER MEASUREMENT INFORMATION

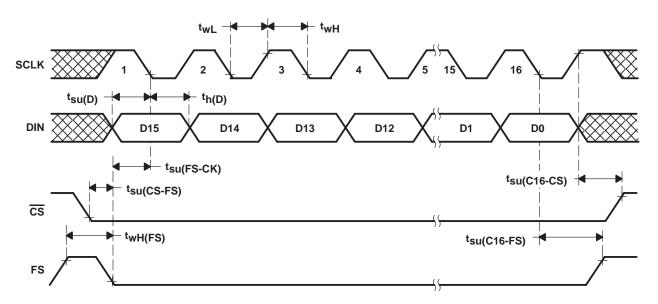
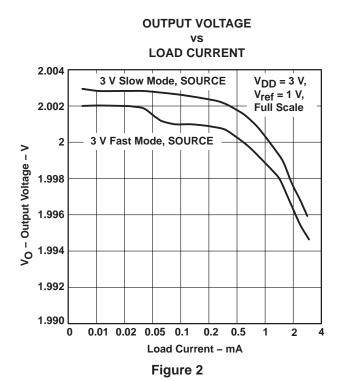
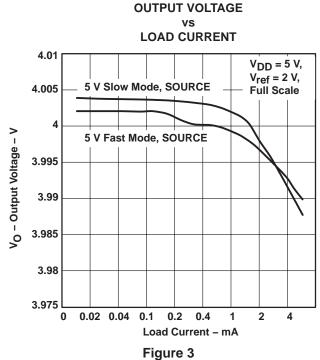


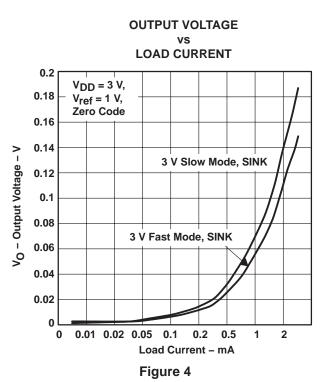
Figure 1. Timing Diagram

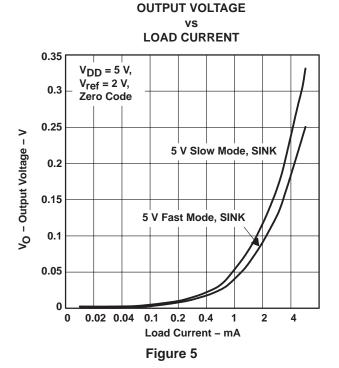


#### **TYPICAL CHARACTERISTICS**

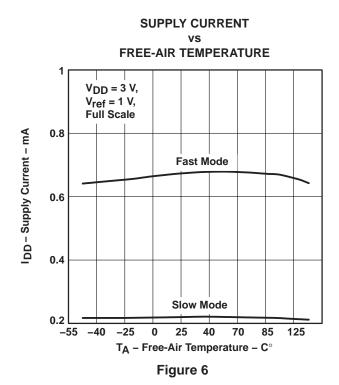


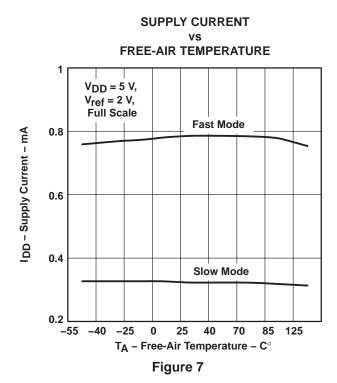


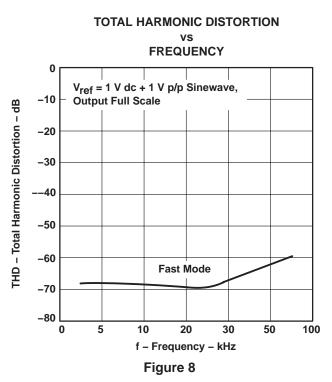


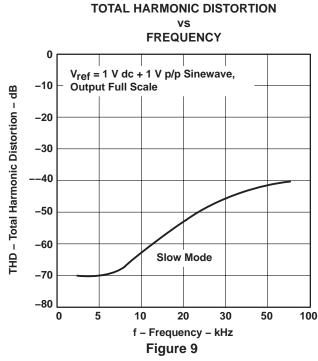


#### TYPICAL CHARACTERISTICS









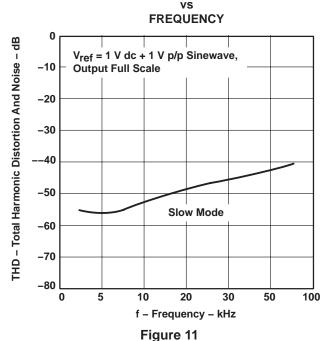
#### **TYPICAL CHARACTERISTICS**

#### TOTAL HARMONIC DISTORTION AND NOISE **FREQUENCY** 0 THD - Total Harmonic Distortion And Noise - dB Vref = 1 V dc + 1 V p/p Sinewave, -10 Output Full Scale -20 -30 --40 -50 **Fast Mode** -60 -70 -80 5 10 20 100 30 50 0

f - Frequency - kHz

Figure 10

TOTAL HARMONIC DISTORTION AND NOISE



# SUPPLY CURRENT





#### TYPICAL CHARACTERISTICS

#### INTEGRAL NONLINEARITY ERROR INL - Integral Nonlinearity Error - LSB 2 1.5 1 0.5 0 -0.5 -1.5 -2 -2.5 -3 -3.5 768 1024 1280 1536 1792 2048 2304 2560 2816 3072 3328 3584 3840 0 256 **Digital Code**

Figure 13

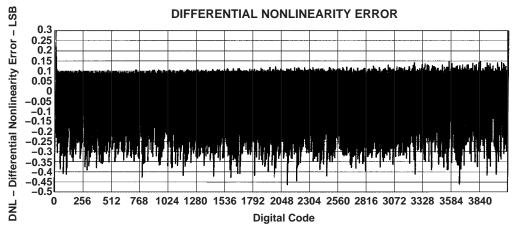


Figure 14



#### **APPLICATION INFORMATION**

### general function

The TLV5616 is a 12-bit single supply DAC based on a resistor string architecture. The device consists of a serial interface, speed and power-down control logic, a reference input buffer, a resistor string, and a rail-to-rail output buffer.

The output voltage (full scale determined by external reference) is given by:

$$2 REF \frac{CODE}{2^n} [V]$$

where REF is the reference voltage and CODE is the digital input value within the range of  $0_{10}$  to  $2^{n-1}$ , where n = 12 (bits). The 16-bit data word, consisting of control bits and the new DAC value, is illustrated in the *data* format section. A power-on reset initially resets the internal latches to a defined state (all bits zero).

#### serial interface

Explanation of data transfer: First, the device has to be enabled with  $\overline{CS}$  set to low. Then, a falling edge of FS starts shifting the data bit-per-bit (starting with the MSB) to the internal register on the falling edges of SCLK. After 16 bits have been transferred or FS rises, the content of the shift register is moved to the DAC latch which updates the voltage output to the new level.

The serial interface of the TLV5616 can be used in two basic modes:

- Four wire (with chip select)
- Three wire (without chip select)

Using chip select (four wire mode), it is possible to have more than one device connected to the serial port of the data source (DSP or microcontroller). The interface is compatible with the TMS320 family. Figure 15 shows an example with two TLV5616s connected directly to a TMS320 DSP.

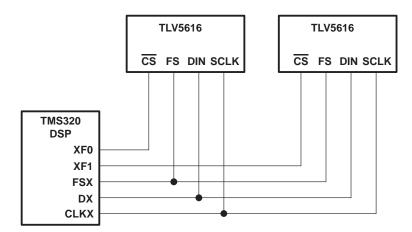


Figure 15. TMS320 Interface

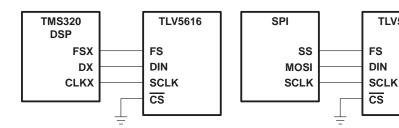


#### APPLICATION INFORMATION

#### serial interface (continued)

If there is no need to have more than one device on the serial bus, then  $\overline{CS}$  can be tied low. Figure 16 shows an example of how to connect the TLV5616 to a TMS320, SPI, or Microwire port using only three pins.

TLV5616



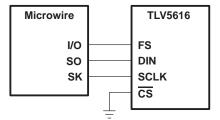


Figure 16. Three-Wire Interface

Notes on SPI and Microwire: Before the controller starts the data transfer, the software has to generate a falling edge on the I/O pin connected to FS. If the word width is 8 bits (SPI and Microwire), two write operations must be performed to program the TLV5616. After the write operation(s), the DAC output is updated automatically on the next positive clock edge following the sixteenth falling clock edge.

#### serial clock frequency and update rate

The maximum serial clock frequency is given by:

$$f_{SCLKmax} = \frac{1}{t_{wH(min)} + t_{wL(min)}} = 20 \text{ MHz}$$

The maximum update rate is:

$$f_{UPDATEmax} = \frac{1}{16 \left(t_{wH(min)} + t_{wL(min)}\right)} = 1.25 \text{ MHz}$$

The maximum update rate is a theoretical value for the serial interface, since the settling time of the TLV5616 has to be considered also.

#### data format

The 16-bit data word for the TLV5616 consists of two parts:

Control bits (D15...D12) (D11...D0) New DAC value

	D15	D14	D13	D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
I	Χ	SPD	PWR	Х		New DAC value (12 bits)										

X: don't care

SPD: Speed control bit. 1 → fast mode  $0 \rightarrow slow mode$ PWR: Power control bit.  $1 \rightarrow$  power down 0 → normal operation

In power-down mode, all amplifiers within the TLV5616 are disabled.



#### APPLICATION INFORMATION

#### TLV5616 interfaced to TMS320C203 DSP

#### hardware interfacing

Figure 17 shows an example how to connect the TLV5616 to a TMS320C203 DSP. The serial interface of the TLV5616 is ideally suited to this configuration, using a maximum of four wires to make the necessary connections. In applications where only one synchronous serial peripheral is used, the interface can be simplified even further by pulling  $\overline{CS}$  low all the time as shown in the figure.

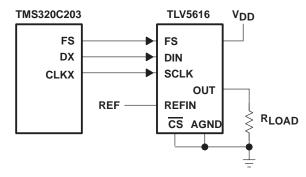


Figure 17. TLV5616 to DSP Interface

#### software

No setup procedure is needed to access the TLV5616. The output voltage can be set using just a single command.

```
out data addr, SDTR
```

where data\_addr points to an address location holding the control bits and the 12 data bits providing the output voltage data. SDTR is the address of the transmit FIFO of the synchronous serial port.

The following code shows how to use the timer of the TMS320C203 as a time base to generate a voltage ramp with the TLV5616.

A timer interrupt is generated every 205  $\mu$ s. The corresponding interrupt service routine increments the output code (stored at 0x0064) for the DAC, adds the DAC control bits to the four most significant bits, and writes the new code to the TLV5616. The resulting period of the saw waveform is:

```
\pi = 4096 \times 205 \text{ E-6 s} = 0.84 \text{ s}
```

```
;* Title : Ramp generation with TLV5616
;* Version : 1.0
;* DSP
         : TI TMS320C203
;* © (1998) Texas Instruments Incorporated
;----- I/O and memory mapped regs -----
      .include "regs.asm"
 ----- vectors -----
      .ps
              0h
      b
               start
      b
               INT1
               INT23
               TIM ISR
```



#### **APPLICATION INFORMATION**

```
;* Main Program
           1000h
    .ps
     .entry
start:
; disable interrupts
                      ; disable maskable interrupts
     setc INTM
            #Offffh, IFR
     splk
            #0004h, IMR
     splk
; set up the timer to interrupt ever 205uS
           #0000h, 60h
     splk
            #00FFh, 61h
     splk
     out
           61h, PRD
            60h, TIM
           #0c2fh, 62h
     splk
            62h, TCR
     out
; Configure SSP to use internal clock, internal frame sync and burst mode
         #0CC0Eh, 63h
     splk
            63h, SSPCR
     out
            #0CC3Eh, 63h
     splk
            63h, SSPCR
     out
            #0000h, 64h; set initial DAC value
     splk
; enable interrupts
            INTM
                     ; enable maskable interrupts
     clrc
; loop forever!
     idle
next:
                      ; wait for interrupt
       b
            next
; all else fails stop here
                      ; hang there
done: b done
;* Interrupt Service Routines
*********************
INT1:
       ret
                      ; do nothing and return
INT23:
       ret
                      ; do nothing and return
TIM_ISR:
                     ; restore counter value to ACC
       lacl
           64h
                     ; increment DAC value
       add
            #1h
            #0FFFh
       and
                      ; mask 4 MSBs
                      ; store 12 bit counter value
       sacl 64h
                      ; set DAC control bits
            #4000h
       or
       sacl 65h
                      ; store DAC value
       out 65h, SDTR ; send data
                     ; re-enable interrupts
       clrc intm
       ret
.END
```



#### APPLICATION INFORMATION

#### TLV5616 interfaced to MCS51® microcontroller

#### hardware interfacing

Figure 18 shows an example of how to connect the TLV5616 to an MCS51<sup>®</sup> compatible microcontroller. The serial DAC input data and external control signals are sent via I/O port 3 of the controller. The serial data is sent on the RxD line, with the serial clock output on the TxD line. P3.4 and P3.5 are configured as outputs to provide the chip select and frame sync signals for the TLV5616.

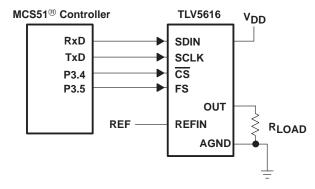


Figure 18. TLV5616 to MCS51® Controller Interface

#### software

The example program puts out a sine wave on the OUT pin.

The on-chip timer is used to generate interrupts at a fixed frequency. The related interrupt service routine fetches and writes the next sample to the DAC. The samples are stored in a lookup table, which describes one full period of a sine wave.

The serial port of the controller is used in mode 0, which transmits 8 bits of data on RxD, accompanied by a synchronous clock on TxD. Two writes concatenated together are required to write a complete word to the TLV5616. The CS and FS signals are provided in the required fashion through control of I/O port 3, which has bit addressable outputs.

```
;* Title : Ramp generation with TLV5616
;* Version : 1.0
; * MCU : INTEL MCS51®
* © (1998) Texas Instruments Incorporated
; Program function declaration
NAME
      GENSINE
MAIN
      SEGMENT
                   CODE
ISR
      SEGMENT
                   CODE
SINTBL SEGMENT
                   CODE
VAR1
      SEGMENT
                   DATA
STACK SEGMENT
                   IDATA
; Code start at address 0, jump to start
   CSEG AT 0
```

MCS is a registered trademark of Intel Corporation



#### **APPLICATION INFORMATION**

```
LJMP
                     ; Execution starts at address 0 on power-up.
            start
;------
; Code in the timerO interrupt vector
  CSEG AT OBH
          timer0isr; Jump vector for timer 0 interrupt is 000Bh
;------
; Define program variables
        VAR1
   RSEG
rolling ptr: DS 1
; Interrupt service routine for timer 0 interrupts
   RSEG
            ISR
timerOisr:
   PUSH
          PSW
          ACC
   PUSH
                        ; set CSB low
   CLR
            T0
   CLR
                           ; set FS low
   ; The signal to be output on the dac is a sine function. One cycle of a sine wave is
   ; held in a table @ sinevals as 32 samples of msb, lsb pairs (64 bytes). The pointer,
   ; rolling ptr, rolls round the table of samples incrementing by 2 bytes (1 sample) on
   ; each interrupt (at the end of this routine).
            DPTR, #sinevals ; set DPTR to the start of the table of sine signal values
   MOV
            A, rolling ptr ; ACC loaded with the pointer into the sine table
   MOV
                         ; get msb from the table
   MOVC
            A,@A+DPTR
                          ; set control bits
   ORL
            A, #00H
   MOV
            SBUF,A
                          ; send out msb of data word
   MOVA, rolling ptr; move rolling pointer in to ACC
                        ; increment ACC holding the rolling pointer
; which is the lsb of this sample, now in ACC
   MOVC
            A,@A+DPTR
MSB TX:
            TI, MSB_TX ; wait for transmit to complete
   JNB
                          ; clear for new transmit ; and send out the lsb
   CLR
            ΤI
  MOV
            SBUF,A
LSB TX:
                         ; wait for lsb transmit to complete
   JNB
            TI, LSB TX
                          ; set FS = 1
   SETB
            Т1
            ΤI
                          ; clear for new transmit
   CLR
   MOV
         A, rolling ptr
                          ; load ACC with rolling pointer
                          ; increment the ACC twice, to get next sample
   INC
         Α
   TNC
                         ; wrap back round to 0 if >64
   ANL
         A,#03FH
                          ; move value held in ACC back to the rolling pointer
   MOV
         rolling_ptr,A
   SETB
                          ; CSB high
   POP
         ACC
   POP
   RETI
; Set up stack
```



#### **APPLICATION INFORMATION**

```
RSEG STACK
      10h
                         ; 16 Byte Stack!
  DS
;------
; Main Program
  RSEG MAIN
start:
  MOV
        SP, #STACK-1; first set Stack Pointer
  CLR
                    ; set serial port 0 to mode 0
  MOV
       SCON, A
  MOV
        TMOD, #02H ; set timer 0 to mode 2 - auto-reload
                    ; set THO for 16.67 kHs interrupts
  MOV
        TH0, #0C8H
  SETB T1
SETB T0
                    ; set FS = 1
                     ; set CSB = 1
  SETB ET0
                    ; enable timer 0 interrupts
                    ; enable all interrupts
  SETB EA
  MOV
         rolling_ptr,A
                          ; set rolling pointer to 0
  SETB
       TR0
                          ; start timer 0
always:
  SJMP
        always
                          ; while(1) !
  RET
; Table of 32 sine wave samples used as DAC data
  RSEG SINTBL
sinevals:
  DW
         01000H
  DW
         0903EH
  DM
        05097H
  DW
        0305CH
  DW
        0B086H
  DW
       070CAH
  DM
        OFOEOH
  DW
        OF06EH
  DW
        0F039H
  DW
         OF06EH
  DW
        OFOEOH
  DW
        070CAH
  DW
       0B086H
  DW
        0305CH
  DW
        05097H
  DW
        0903EH
  DW
        01000H
  DW
        06021H
  DW
        0A0E8H
  DW
        0C063H
  DW
        040F9H
  DW
        080B5H
  DW
        0009FH
  DW
        00051H
  DW
        00026H
  DW
        00051H
  DW
         0009FH
  DW
         080B5H
  DW
         040F9H
  DW
        0C063H
  DW
        0A0E8H
  DW
        06021H
END
```



#### **APPLICATION INFORMATION**

#### linearity, offset, and gain error using single ended supplies

When an amplifier is operated from a single supply, the voltage offset can still be either positive or negative. With a positive offset, the output voltage changes on the first code change. With a negative offset, the output voltage may not change with the first code, depending on the magnitude of the offset voltage.

The output amplifier attempts to drive the output to a negative voltage. However, because the most negative supply rail is ground, the output cannot drive below ground and clamps the output at 0 V.

The output voltage then remains at zero until the input code value produces a sufficient positive output voltage to overcome the negative offset voltage, resulting in the transfer function shown in Figure 19.

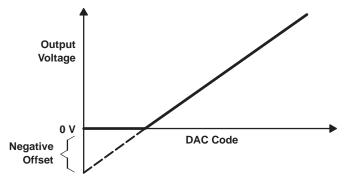


Figure 19. Effect of Negative Offset (Single Supply)

This offset error, not the linearity error, produces this breakpoint. The transfer function would have followed the dotted line if the output buffer could drive below the ground rail.

For a DAC, linearity is measured between zero-input code (all inputs 0) and full-scale code (all inputs 1) after offset and full scale are adjusted out or accounted for in some way. However, single supply operation does not allow for adjustment when the offset is negative due to the breakpoint in the transfer function. So the linearity is measured between full-scale code and the lowest code that produces a positive output voltage.

#### power-supply bypassing and ground management

Printed-circuit boards that use separate analog and digital ground planes offer the best system performance. Wire-wrap boards do not perform well and should not be used. The two ground planes should be connected together at the low-impedance power-supply source. The best ground connection may be achieved by connecting the DAC AGND terminal to the system analog ground plane, making sure that analog ground currents are well managed and there are negligible voltage drops across the ground plane.

A 0.1- $\mu$ F ceramic-capacitor bypass should be connected between  $V_{DD}$  and AGND and mounted with short leads as close as possible to the device. Use of ferrite beads may further isolate the system analog supply from the digital power supply.

Figure 20 shows the ground plane layout and bypassing technique.

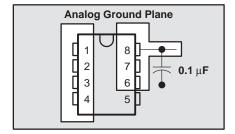


Figure 20. Power-Supply Bypassing



SLAS152D - DECEMBER 1997 - REVISED APRIL 2004

#### APPLICATION INFORMATION

#### definitions of specifications and terminology

#### integral nonlinearity (INL)

The relative accuracy or integral nonlinearity (INL), sometimes referred to as linearity error, is the maximum deviation of the output from the line between zero and full scale excluding the effects of zero code and full-scale errors.

#### differential nonlinearity (DNL)

The differential nonlinearity (DNL), sometimes referred to as differential error, is the difference between the measured and ideal 1 LSB amplitude change of any two adjacent codes. Monotonic means the output voltage changes in the same direction (or remains constant) as a change in the digital input code.

#### zero-scale error (E<sub>ZS</sub>)

Zero-scale error is defined as the deviation of the output from 0 V at a digital input value of 0.

#### gain error (E<sub>G</sub>)

Gain error is the error in slope of the DAC transfer function.

#### signal-to-noise ratio + distortion (S/N+D)

S/N+D is the ratio of the rms value of the output signal to the rms sum of all other spectral components below the Nyquist frequency, including harmonics but excluding dc. The value for S/N+D is expressed in decibels.

#### spurious free dynamic range (SFDR)

SFDR is the difference between the rms value of the output signal and the rms value of the largest spurious signal within a specified bandwidth. The value for SFDR is expressed in decibels.

#### total harmonic distortion (THD)

THD is the ratio of the rms sum of the first six harmonic components to the rms value of the fundamental signal and is expressed in decibels.









#### **PACKAGING INFORMATION**

Orderable Device	Status <sup>(1)</sup>	Package Type	Package Drawing	Pins	Package Qty	e Eco Plan <sup>(2)</sup>	Lead/Ball Finish	MSL Peak Temp <sup>(3)</sup>
TLV5616CD	ACTIVE	SOIC	D	8	75	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
TLV5616CDG4	ACTIVE	SOIC	D	8	75	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
TLV5616CDGK	ACTIVE	MSOP	DGK	8	80	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
TLV5616CDGKG4	ACTIVE	MSOP	DGK	8	80	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
TLV5616CDR	ACTIVE	SOIC	D	8	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
TLV5616CDRG4	ACTIVE	SOIC	D	8	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
TLV5616CP	ACTIVE	PDIP	Р	8	50	Pb-Free (RoHS)	CU NIPDAU	N / A for Pkg Type
TLV5616CPE4	ACTIVE	PDIP	Р	8	50	Pb-Free (RoHS)	CU NIPDAU	N / A for Pkg Type
TLV5616ID	ACTIVE	SOIC	D	8	75	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
TLV5616IDG4	ACTIVE	SOIC	D	8	75	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
TLV5616IDGK	ACTIVE	MSOP	DGK	8	80	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
TLV5616IDGKG4	ACTIVE	MSOP	DGK	8	80	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
TLV5616IDGKR	ACTIVE	MSOP	DGK	8	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
TLV5616IDGKRG4	ACTIVE	MSOP	DGK	8	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
TLV5616IDR	ACTIVE	SOIC	D	8	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
TLV5616IDRG4	ACTIVE	SOIC	D	8	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
TLV5616IP	ACTIVE	PDIP	Р	8	50	Pb-Free (RoHS)	CU NIPDAU	N / A for Pkg Type
TLV5616IPE4	ACTIVE	PDIP	Р	8	50	Pb-Free (RoHS)	CU NIPDAU	N / A for Pkg Type

<sup>&</sup>lt;sup>(1)</sup> The marketing status values are defined as follows:

**ACTIVE:** Product device recommended for new designs.

**LIFEBUY:** TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

**NRND:** Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

TBD: The Pb-Free/Green conversion plan has not been defined.

**Pb-Free** (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

Pb-Free (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and

<sup>(2)</sup> Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.



#### PACKAGE OPTION ADDENDUM

28-Aug-2008

package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

(3) MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

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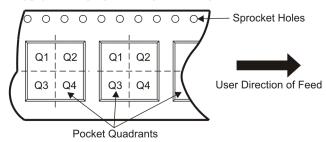
#### TAPE AND REEL INFORMATION





	Dimension designed to accommodate the component width
B0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



#### \*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
TLV5616CDR	SOIC	D	8	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1
TLV5616IDGKR	MSOP	DGK	8	2500	330.0	12.4	5.3	3.4	1.4	8.0	12.0	Q1
TLV5616IDR	SOIC	D	8	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1





\*All dimensions are nominal

ń	7 III GIIII GIIGI GIIG GIIG II GII III I							
	Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
	TLV5616CDR	SOIC	D	8	2500	346.0	346.0	29.0
	TLV5616IDGKR	MSOP	DGK	8	2500	346.0	346.0	29.0
	TLV5616IDR	SOIC	D	8	2500	346.0	346.0	29.0

# DGK (S-PDSO-G8)

# PLASTIC SMALL-OUTLINE PACKAGE



NOTES:

- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.15 per end.
- Body width does not include interlead flash. Interlead flash shall not exceed 0.50 per side.
- E. Falls within JEDEC MO-187 variation AA, except interlead flash.



# D (R-PDSO-G8)

## PLASTIC SMALL-OUTLINE PACKAGE



NOTES:

- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed .006 (0,15) per end.
- Body width does not include interlead flash. Interlead flash shall not exceed .017 (0,43) per side.
- E. Reference JEDEC MS-012 variation AA.



#### P (R-PDIP-T8)

#### PLASTIC DUAL-IN-LINE



NOTES: A. All linear dimensions are in inches (millimeters).

- B. This drawing is subject to change without notice.
- C. Falls within JEDEC MS-001

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